TOSHIBA GATE TURN-OFF THYRISTOR LOW SNUBBER TYPE

## SG4000GXH28

## **INVERTER APPLICATION**

Unit in mm

Repetitive Peak Off-State Voltage: VDRM=4500V R.M.S On-State Current  $: I_{T(RMS)} = 1900A$ :  $I_{TGQM} = 4000A$ Peak Turn-Off Current

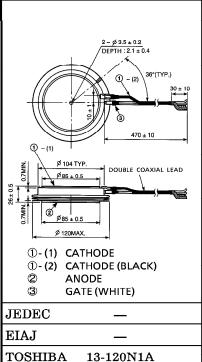
Critical Rate of Rise of On-State Current :  $di/dt = 500A/\mu s$ 

Critical Rate of Rise of Off-State Voltage: dv/dt=1000V/\mu s

Suitable for 3000V DC Off-State Voltage Application

## **MAXIMUM RATINGS**

CHARACTERISTIC	SYMBOL	RATING	UNIT
Repetitive Peak Off-State Voltage (Note 1)	V <sub>DRM</sub>	4500	V
Repetitive Peak Reverse Voltage	V <sub>RRM</sub>	17	V
Peak Turn-Off Current (Note 2)	ITGQM	4000 (6μF) 3000 (3μF)	A
R.M.S On-State Current (Note 3)	I <sub>T (RMS)</sub>	1900	Α
Peak One Cycle Surge On-State Current (Non Repetitive, 10ms-Width Half Sine Waveform)	I <sub>TSM</sub>	20000	A
Critical Rate of Rise of On-State Current (Note 4)	di/dt	500	A/μs
Peak Forward Gate Current	I <sub>FGM</sub>	100	Α
Average Forward Gate Power Dissipation	P <sub>FG (AV)</sub>	100	W
Average Reverse Gate Power Dissipation	P <sub>RG (AV)</sub>	300	W
R.M.S Gate Current (Note 5)	I <sub>G</sub> (RMS)	84	Α
Peak Reverse Gate Voltage (at Static)	$V_{RGM}$	17	V
Operating Junction Temperature Range	T <sub>j</sub> -40~125		°C
Storage Temperature Range	$T_{ m stg}$	g -40~150	
Mounting Force	_	33.3~44.1	kN



Weight: 1700g

Note 1:  $V_{GK} = -2V$ 

Note 2 :  $V_{DM} = 4500V$ ,  $C_S = 6\mu F$  or  $3\mu F$ ,  $di_{GQ}/dt = 50A/\mu s$ ,  $V_{DSP} \le 1200V$  ( $C_S = 6\mu F$ ),

 $L_S \leq 0.2 \mu H$  (TOSHIBA method)

Note 3: 50Hz Half Sine Waveform at Tf=71°C

Note 4 :  $V_D = 3000V$ ,  $I_{GM} \ge 25A$ 

Note 5: Ambient Temperature of coaxial gate-cathode lead=90°C

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## **ELECTRICAL CHARACTERISTICS**

CHARACTERISTIC	SYMBOL	TEST CONDITION		MIN.	TYP.	MAX.	UNIT
Repetitive Peak Off-State Current	$I_{ m DRM}$	$V_{ m DRM} = 4500  m V, \ V_{ m GK} = -2  m V, \ T_{ m j} = 125  m ^{\circ} C$		_	_	100	mA
Repetitive Peak Reverse Current	$I_{ m RRM}$	$V_{ m RRM} = 17 V, \ T_{ m j} = 125 { m ^{\circ} C}$		_		10	mA
Repetitive Peak Reverse Gate Current	$I_{ m RGM}$	$V_{ m RGM} = 17V, \ T_{ m j} = 125^{\circ}{ m C}$		_	-	10	mA
Peak On-State Voltage	$v_{ m TM}$	I <sub>TM</sub> =4000A, T <sub>j</sub> =125°C		_	_	4.0	V
Gate Trigger Voltage	$v_{GT}$	$V_{\mathrm{D}}$ = 24V, $R_{\mathrm{L}}$ = 0.1 $\Omega$	$T_j = -40$ °C	_	_	_	V
			$T_j = 25^{\circ}C$	_	_	1.5	
Gate Trigger Current	${ m I_{GT}}$		$T_j = -40$ °C		_	_	A
			$T_j = 25$ °C	_	_	4.0	
Turn-On Delay Time	t <sub>d</sub>	$V_{ m D}\!=\!2800{ m V,\ di/dt}\!=\!500{ m A}/\mu{ m s,} \ I_{ m GM}\!=\!25{ m A,\ T_j}\!=\!25^{ m o}{ m C,} \ I_{ m TM}\!=\!4000{ m A}$		<u> </u>	_	3.0	$\mu$ s
Turn-On Time	$t_{\mathrm{gt}}$			_	_	10	μs
Critical Rate of Rise of Off- State Voltage	dv/dt	$V_D$ =3000V, $V_{GK}$ =-10V, Exponential Rise, $T_j$ =125°C		1000	_	_	V/μs
Storage Time	$t_{\mathrm{S}}$	$\begin{split} &I_{TGQ}\!=\!4000\text{A}, V_{DM}\!=\!4500\text{V},\\ &R_{S}\!=\!5\Omega, V_{D}\!=\!2800\text{V},\\ &\text{di}_{GQ}/\text{dt}\!=\!50\text{A}/\mu\text{s}, C_{S}\!=\!6\mu\text{F},\\ &V_{DSP}\!\!\leq\!1200\text{V}, T_{j}\!=\!125^{\circ}\text{C},\\ &L_{S}\!\leq\!0.2\mu\text{H} \end{split}$		_	_	33	μs
Gate Turn-Off Time	$\mathbf{t}_{\mathrm{gq}}$				_	35	μs
Tail Time	t <sub>tail</sub>			_	_	150	$\mu$ s
Gate Turn-Off Current	$I_{\mathbf{GQ}}$			_	940	_	Α
Thermal Resistance (Junction to Fin)	$ m R_{th~(j-f)}$	DC		_	_	0.011	°C/W

